FORM PTO-1449
U.S. DEPARTMENT OF COMMERCE
(Modified)
PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

RE-EXAM C
APPLICAN

(Use several sheets if necessary)

(37 CFR 1.98(b))

ATTY, DOCKET NO.:

| SERIAL NO.:
| O-607109

RE-EXAM CONTROL NO.;
APPLICANT; Hollander et al.

FILING DATE

GROUP:

REFERENCE DI	ESIGNATION	U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB- CLASS	FIUNG DATE IF APPROPRIATE		
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1	3,823,313	7/1974	Unema	362	259			
- 1	4,315,150	2/1982	Darringer et al.	374	130	7.7		
	4,330,212	5/1982	Miller	356	354			
	4,494,881	1/1985	Everest	374	124	1		
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	4,582,426	4/1986	Douglas	374	121			
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·		DOCUMENT NUMBER	1	COUNTRY OR]	SUB-	TRANSLATION	
1.1 >		DATE	PATENT OFFICE	CLASS	CLASS	YES	NO.	
- HAY	-	GB 2,203,537A	10-19-98	Great Britain				
DJV.	 	62-12848	2/1982	Japan	374	121		
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McCormick, F. B., "Generation of Large Spot Arrays From a Single Laser Beam by Multiple Imaging with Binary Phase Gratings," Optical Engineering, April 1989, Vol. 28 No. 4, pp. 299-304.

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5-20-04

EXAMINER: Initial it reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to

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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY, DOCKET NO .:

SERIAL, NO .:

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

RE-EXAM CONTROL NO .:

APPLICANT: Hollander et al.

(Use several sheets if necessary) (37 CFR 1.98(b))

FILING DATE!

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REFERENCE DES	GIGNATION	U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB- CLASS	FILING DATE IF		
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-	0458200A3		European Pat.				ļ
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